

Notice of References Cited	Application/Control No. 10/525,194		Applicant(s)/Patent Under Reexamination SAITOH ET AL.	
	Examiner Dawn Garrett		Art Unit 1794	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
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	K	US-			
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FOREIGN PATENT DOCUMENTS

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	N	JP 2003-128651 A	05-2003	Japan	Ishida et al.	---
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NON-PATENT DOCUMENTS

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	U	Proceedings of SPIE, (1998), 3472, p. 70-79.
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